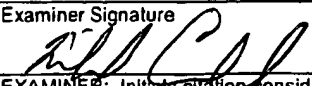
Sheet 1 of 1

Substitute Form PTO-1449 (Modified) Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CFR §1.98(b))	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 05770-156002	Application No. 10/673,307
	Applicant Martin W. Rupich et al.		
	Filing Date September 29, 2003	Group Art Unit 1762	

U.S. Patent Documents							
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate

Foreign Patent Documents or Published Foreign Patent Applications								
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No

Other Documents (include Author, Title, Date, and Place of Publication)		
Examiner Initial	Desig. ID	Document
<i>MD</i>	AA	G. Risse et al., "Textured YBCO-Film Formation by Sol-Gel Process and Post Annealing," Journal of European Ceramic Society 19 (1999) 125-130.
<i>MD</i>	AB	Office Action received in Korean Application No. 2003-7005637, dated July 29, 2005.

Examiner Signature 	Date Considered 2/13/05
EXAMINER: Initials and date considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	

Sheet 1 of 1

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Foreign Patent Documents or Published Foreign Patent Applications

Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
MBC	AA	WO 99/35083	07/15/99	PCT	—	—	abstract	

Other Documents (include Author, Title, Date, and Place of Publication)

Examiner Initial	Desig. ID	Document
MBC	AB	Koster et al., "Influence of the Surface Treatment on the Homoepitaxial Growth of SrTiO ₃ ", <i>Materials Science & Engineering B56</i> , (1998) p. 209-212
MBC	AC	Rupich et al., "Growth and Characterization of Oxide Buffer Layers for YBCO Coated Conductors", <i>IEEE Trans. on Appl. Superconductivity</i> , Vol. 9, (1999), pp. 1527-1530
MBC	AD	Tanaka et al., "Improvement of YBa ₂ Cu ₃ O _x Single-Crystal Surface by Chemical Etching", <i>Jpn. J. Appl. Phys.</i> , Vol. 38 (1999) p. L731-L733

Examiner Signature 	Date Considered 2/13/06
EXAMINER: Initials of examiner considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	

Substitute Form PTO-1449 (Modified) Information Disclosure Statement Prepared by Applicant (Use several sheets if necessary) (37 CFR §1.98(b))	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 05770-156002	Application No. 10/673,307
	Applicant Martin W. Rupich et al.		
	Filing Date September 29, 2003	Group Art Unit 1762	

U.S. Patent Documents

Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
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Foreign Patent Documents or Published Foreign Patent Applications

Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
<i>MRP</i>	AA	0 277 020	8/3/1988	EPO	—	—		
<i>MRP</i>	AB	0 301 591	2/1/1989	EPO	—	—		
<i>MRP</i>	AC	0 349 444	1/3/1990	EPO	—	—		
<i>MRP</i>	AD	0 431 813	6/12/1991	EPO	—	—		

Other Documents (include Author, Title, Date, and Place of Publication)

Examiner Initial	Desig. ID	Document
<i>MRP</i>	AE	Office Action received in European Application No. 01 988 951.8, dated November 22, 2005.

Examiner Signature <i>MRP</i>	Date Considered <i>2/13/06</i>
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	